Annex A: System Check
Tested Model : X109
Report Number: WSCT-ANAB-R&E250900073A-SAR

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Measurement Report for Device, , , UID 0 -, Channel 0 (2550.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	2550.000, 0	6.94	1.90	40.8

Hardware Setup

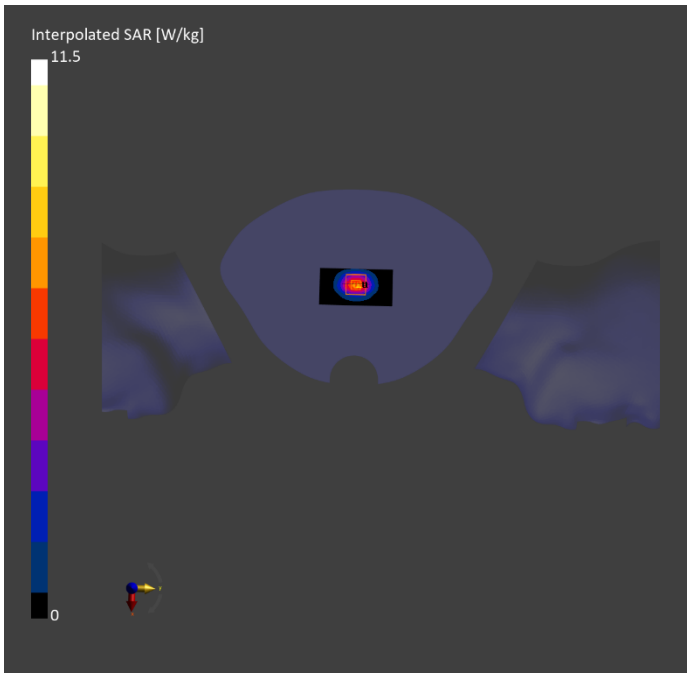
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-15	2025-09-15
psSAR1g [W/kg]	5.48	5.58
psSAR10g [W/kg]	2.53	2.56
Power Drift [dB]	0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.5
Dist 3dB Peak [mm]		9.0



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Measurement Report for Device, , , UID 0 -, Channel 0 (5200.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5200.000, 0	5.34	4.54	36.3

Hardware Setup

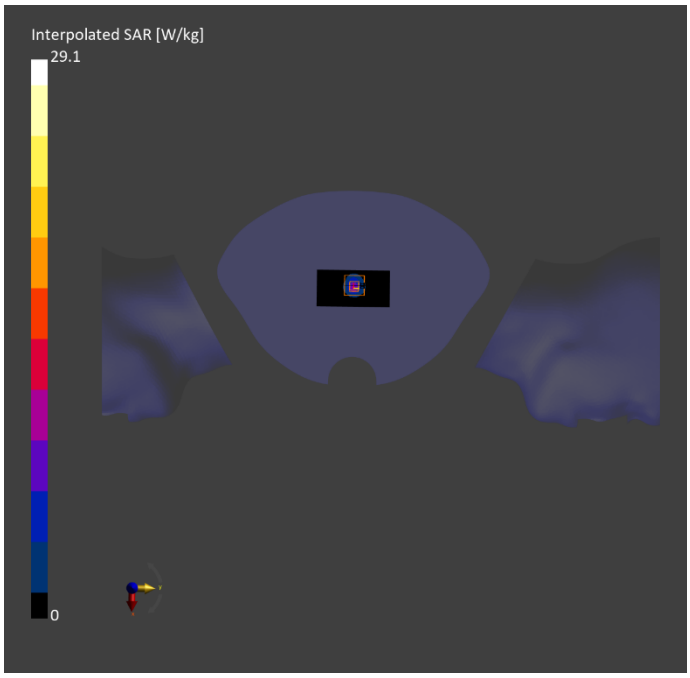
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-16	2025-09-16
psSAR1g [W/kg]	6.41	7.17
psSAR10g [W/kg]	1.91	2.07
Power Drift [dB]	0.02	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.3
Dist 3dB Peak [mm]		7.2



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Measurement Report for Device, , , UID 0 -, Channel 0 (5300.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5300.000, 0	5.28	4.65	36.2

Hardware Setup

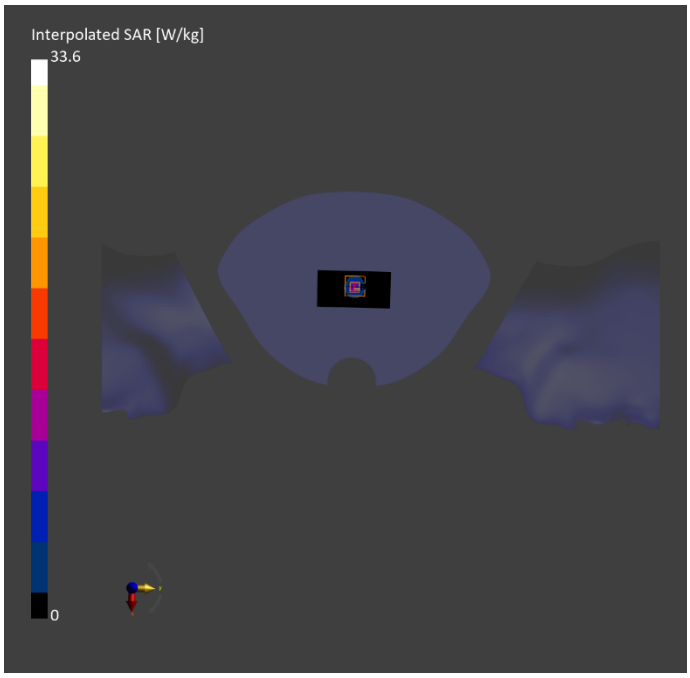
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-16	2025-09-16
psSAR1g [W/kg]	7.15	8.08
psSAR10g [W/kg]	2.09	2.31
Power Drift [dB]	0.01	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.4
Dist 3dB Peak [mm]		7.2



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Measurement Report for Device, , , UID 0 -, Channel 0 (5500.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5500.000, 0	4.87	4.88	35.8

Hardware Setup

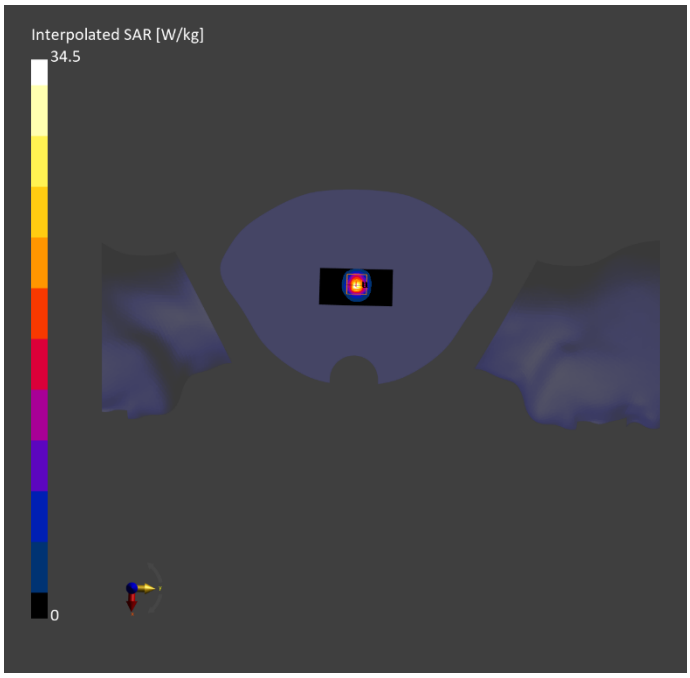
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-16	2025-09-16
psSAR1g [W/kg]	6.98	7.90
psSAR10g [W/kg]	2.03	2.25
Power Drift [dB]	0.03	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		59.5
Dist 3dB Peak [mm]		7.2



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Measurement Report for Device, , , UID 0 -, Channel 0 (5600.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5600.000, 0	4.87	5.00	35.6

Hardware Setup

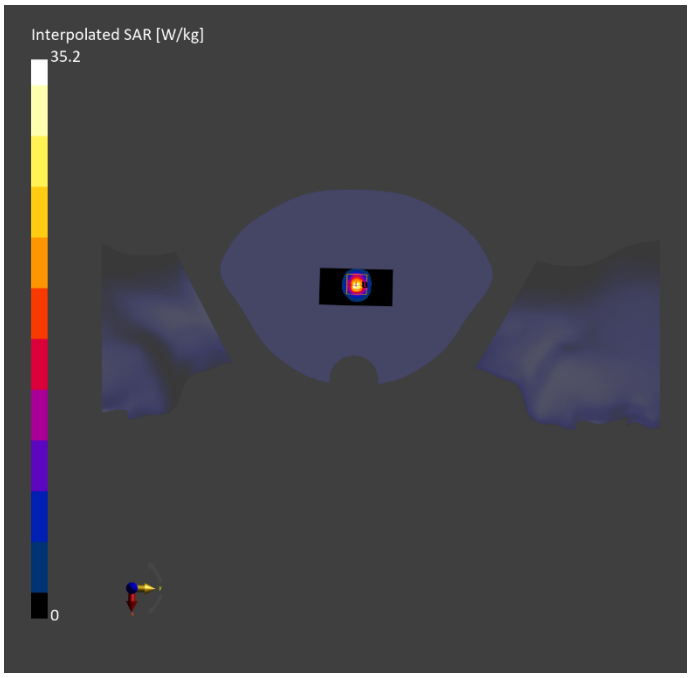
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-17	2025-09-17
psSAR1g [W/kg]	7.00	7.87
psSAR10g [W/kg]	2.04	2.24
Power Drift [dB]	0.02	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		58.4
Dist 3dB Peak [mm]		7.2



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Measurement Report for Device, , , UID 0 -, Channel 0 (5800.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

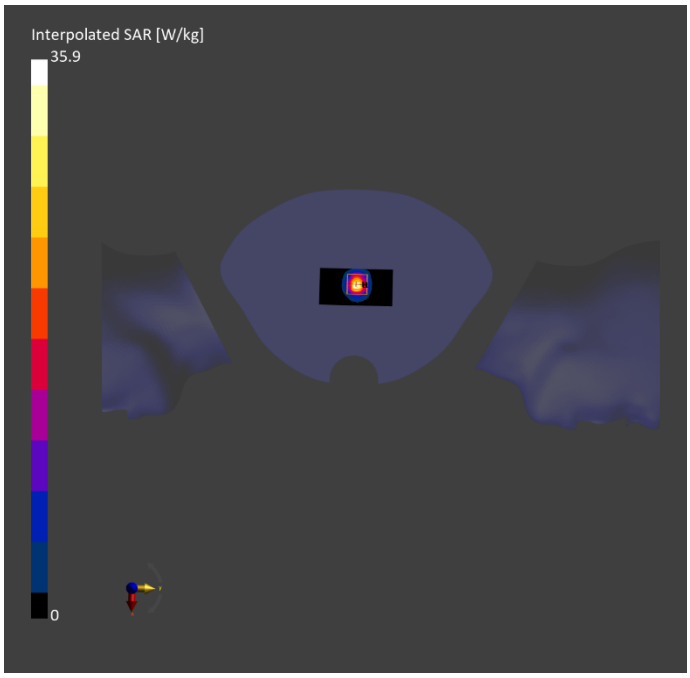
Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5800.000, 0	4.84	5.23	35.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7951, 2025-09-10	DAE4ip Sn1921, 2025-09-04

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-19	2025-09-19
psSAR1g [W/kg]	6.76	7.76
psSAR10g [W/kg]	2.00	2.20
Power Drift [dB]	0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		56.9
Dist 3dB Peak [mm]		7.6